Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	0	((test$3 with (("input low voltage" vil) ("input hi voltage" vih) (input adj levels))) and ((voltage adj generator) DAC) and (sense adj amplifier) with external$2 near (reference adj voltage) with (trip adj point) and (((boundary adj scan) BS) adj register) with (sense adj amplifier) with (compar$3 near reference adj voltage) with (DC adj voltage)).clm.	US-PGPUB	OR	ON	2005/10/27 15:06

Interference Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S67	2	(input near2 (level voltage) near2 test$3).ti. and (Boundary adj scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:54
S71	1	S70 and S69	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:51
S70	15507	(341/94,132,155,158 324/522,523, 527,537,763,765,76.83 714/819, 727,736,734,733,716,30).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:51
S63	14673	(341/94,132,155,158 324/522,523, 527,537,763,765,76.83 714/819, 727,736,734,733,716,30).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:51
S69	2	("input low voltage" vil) and ("input hi voltage" vih) and (interpret$3 near2 logical near2 ((one "1") (zero "0")))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:50
S68	2	(input near2 (level voltage) near2 test$3).ti. and (vil vih)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:47
S62	84	(input near2 (level voltage) near2 test$3).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/27 11:41
S66	12	("6635934" "5490109" "5487036" "6795352" "5490107" "5590074" "6473338").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/17 10:29
S65	32	S63 and S60	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:35
S64	6	S63 and S59	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:35

S61	413	(input near2 (level voltage) near2 test$3).ti,ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:23
S60	808	(input near3 (level voltage) near3 test$3).ti,ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:23
S59	35	((sense near4 amp$6) comparator) and (boundary near3 scan near3 register) and ((DAC D-to-A (D$1A near3 convert$3)) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:21
S30	1040	(sense near4 amp$6) receiver comparator)and (boundary$1scan boundary scan) same test and (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 17:09
S55	74	(external$2 near6 (ramp near4 (generat$3 signal level))) same (((sense op) near4 amp$6) or comparator)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 16:41
S53	239	external$2 near6 (ramp near4 (generat$3 signal level))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 16:39
S54	8	((341/94,132,155,158 324/522,523, 527,537,763,765,76.83 714/819, 727,736,734,733,716,30).ccls. and (external$2 near6 (ramp near4 (generat$3 signal level))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 16:17
S14	0	(341/94,132,155,158).ccls. and (324/522,523,527,537,763,765,76. 83).ccls. and (714/819,727,736, 734,733,716,30).ccls. and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 16:16
S52	183	external near6 (ramp near4 (generat$3 signal level))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 16:14
S51	13	(AC with (I/O or IO or I$1O) with (loopback loop-back loop adj back))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/26 10:08

S50	40	((AC A/C) adj (feedback feed adj back feed-back)) and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/26 09:54
S49	0	((((AC A/C) adj (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))) and (boundary$1scan boundary adj scan boundary-scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/26 09:54
S48	58	((((AC A/C) adj (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))) and test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:47
S45	1	(((((AC A/C) near4 (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))) and (boundary$1scan boundary adj scan boundary-scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:47
S47	269	(((AC A/C) adj (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:46
S46	0	(((AC A/C) adj (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3)) and (boundary$1scan boundary adj scan boundary-scan) same test and ((sense or operational near4 amplifier) or receiver or comparator or op-amp) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:44
S44	0	(((((AC A/C) near4 (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))) and (boundary$1scan boundary adj scan boundary-scan) same test and ((sense or operational near4 amplifier) or receiver or comparator or op-amp) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:42
S43	1389	(((AC A/C) near4 (feedback feed adj back feed-back)) same (test$2 control$2 compar$4 generat$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:38

S42	291	(boundary$1scan boundary scan) same test and ((sense or operational near4 amplifier) or receiver or comparator or op-amp) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3)) and (switch pass near2 gate toogle)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 16:38
S41	287	(boundary$1scan boundary scan) same test and ((sense or operational near4 amplifier) or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3)) and (switch pass near2 gate toogle)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 15:57
S40	268	(boundary$1scan boundary scan) same test and ((sense or operational) near4 amplifier or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3)) and (switch pass near2 gate toogle)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 15:51
S39	202	(boundary$1scan boundary scan) same test and (sense near4 amplifier or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3)) and (switch pass near2 gate toogle)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 15:47
S31	269	(boundary$1scan boundary scan) same test and (sense near4 amplifier or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/25 12:24
S38	1	"6085278".pn.	USPAT	OR	OFF	2004/03/25 12:01
S37	11	DFT and ((loopback loop-back loop adj back) near4 (generat$3 compar$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 16:36
S36	2	structural adj tester	USPAT	OR	OFF	2004/03/24 16:35
S35	4	DFT and ((loopback loop-back loop adj back) near4 (generat$3 compar$4))	USPAT	OR	OFF	2004/03/24 16:35
S34	84	DFT and (loopback loop-back loop adj back)	USPAT	OR	OFF	2004/03/24 15:57

S33	5	((loop adj back loopback loop-back) near4 (compar$3 generat$3)) same test$3 and (sense near4 amplifier or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 15:19
S32	4	((loop$1back loopback) near4 (compar$3 generat$3)) same test$3 and (sense near4 amplifier or receiver or comparator) same (DAC D-to-A (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 15:16
S29	9	(((341/94,132,155,158).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)) and ((sense near4 amp$6) receiver comparator)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 11:37
S28	6	((((324/522,523,527,537,763,765, 76.83).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)) and ((sense near4 amp$6) receiver comparator)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 11:14
S27	25	((((714/819,727,736,734,733,716, 30).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)) and ((sense near4 amp$6) receiver comparator)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 10:10
S26	40	(((714/819,727,736,734,733,716, 30).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 10:06
S25	10	(((341/94,132,155,158).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:57

S24	13	(((324/522,523,527,537,763,765, 76.83).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))) and ((sense near4 amp$6) receiv$3 compar$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:56
S23	10	((341/94,132,155,158).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:51
S22	15	((324/522,523,527,537,763,765,76. 83).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:49
S21	3828	(341/94,132,155,158).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:48
S20	6893	(324/522,523,527,537,763,765,76. 83).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:47
S19	40	((714/819,727,736,734,733,716, 30).ccls.) and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:45
S18	3001	(714/819,727,736,734,733,716,30). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:44
S17	10	(341/94,132,155,158).ccls. and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:42
S16	15	(324/522,523,527,537,763,765,76. 83).ccls. and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:41
S15	40	(714/819,727,736,734,733,716,30). ccls. and scan same test and (DAC (D$1A near3 convert$3) (digital-to-analog near4 convert$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/24 09:40

S13	32	(((714/819,727,736,734,733,716, 30).ccls.) and scan same test) and (DAC (d$1A near3 convert$3) (digital-to-analog near4 convert$3))	USPAT	OR	OFF	2004/03/24 09:35
S10	3881	(324/522,523,527,537,763,765,76. 83).ccls.	USPAT	OR	OFF	2004/03/23 16:58
S9	2384	(714/819,727,736,734,733,716,30). ccls.	USPAT	OR	OFF	2004/03/23 16:58
S12	807	((714/819,727,736,734,733,716, 30).ccls.) and scan same test	USPAT	OR	OFF	2004/03/23 16:45
S11	900	((714/819,727,736,734,733,716, 30).ccls.) and scan	USPAT	OR	OFF	2004/03/23 16:44
S8	1	"4928278".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 16:06
S7	0	"04928278".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 16:06
S6	0	"04928278".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 16:06
S5	7	Matthews-W$.in. and "324"/$3.ccls.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 16:05
S4	179	Matthews-W$.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 10:19
S3	1	"0910675".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 10:18
S2	0	"910675".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2003/12/23 10:17

| S1 | 50 | ("4625310" "5690575" "5293079" "4348759" "4507576" "4800294" "5192881" "5304923" "5336944" "5365167" "5530370" "5604750" "5682352" "5844913" "5951705" "5999013" "6194910" "6202186" "6232759" "6348785" "4523143" "5500603" "5936876" "6043672" "6083848" "4907230" "5353308" "5623500" RE31828 "4504783" "4608669" "4782283" "5049814" "5177440" "5243274" "5258985" "5272434" "5394098" "5524114" "5570034" "5583786" "5610826" "5617531" "5621312" "5680936" "5805611" "5818251" "5878051" "5889936" "5905381").pn. | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | OR | ON | 2003/12/23 10:17 |

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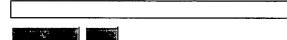☐ Search Session History

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#1   (~~input low voltage~~ <or> vil) and (~~input hi voltage~~ <or> vih) <and> (interpret$3 <near/2> logical <near/2> ((one <or> ~~1~~) <or> (zero <or> ~~0~~)))<in> pdfdata

#2   ((input <near/2> (level <or> voltage) <near/2> test$3) <and> (~~boundary scan~~))<in> pdfdata

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